



CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

Leica Microsystems, Inc.
10 Parkway North Blvd., Suite 300
Deerfield, IL 60015

Fulfills the requirements of

ISO/IEC 17025:2017

In the field of

CALIBRATION

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

A handwritten signature in black ink, appearing to read 'R. Douglas Leonard Jr.', is positioned above a horizontal line.

R. Douglas Leonard Jr., VP, PILR SBU

Expiry Date: 23 February 2024
Certificate Number: AC-1841



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

Leica Microsystems, Inc.
10 Parkway North Blvd., Suite 300
Deerfield, IL 60015
Andrew Suchomski 847-821-3502

CALIBRATION

Valid to: **February 23, 2024**

Certificate Number: **AC-1841**

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Widefield Microscope with Software Measurement Module	Up to 25 mm Up to 0.98 in	6 μ m 240 μ in	Stage Micrometer
Widefield Microscope with Caliper	Up to 25 mm Up to 0.98 in	13 μ m 0.001 1 in	Stage Micrometer

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 ($k=2$), corresponding to a confidence level of approximately 95%.

Notes:

1. On-site calibration service is available for this parameter, since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope.
2. This scope is formatted as part of a single document including Certificate of Accreditation No. AC-1841.



R. Douglas Leonard Jr., VP, PILR SBU